



World Class Accreditation

The American Association for Laboratory Accreditation

Accredited Laboratory

A2LA has accredited

CETECOM MOVON LTD.

Gyeonggi-do, South Korea

for technical competence in the field of

Electrical Testing

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 *General Requirements for the Competence of Testing and Calibration Laboratories*. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (*refer to joint ISO-ILAC-IAF Communiqué dated 8 January 2009*).

Presented this 2nd day of March 2010.



A handwritten signature in black ink, appearing to read "Peter Abney", written over a horizontal line.

President & CEO
For the Accreditation Council
Certificate Number 3021.01
Valid to May 31, 2012

For the tests or types of tests to which this accreditation applies, please refer to the laboratory's Electrical Scope of Accreditation.



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005

CETECOM MOVON LTD.

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ELECTRICAL

Valid To: May 31, 2012

Certificate Number: 3021.01

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following Bluetooth tests:

Test

Test Method

***Bluetooth RF Conformance Test
(Antenna port measurement)***

Bluetooth Program Reference
Documents (PRD) Version 2.1 vd1

Output Power
Power Density
Power Control
Output Spectrum - Frequency Range
Output Spectrum - 20 dB BW
Output Spectrum Adjacent Channel Power
Modulation Characteristics
Initial Carrier Frequency Tolerance
Carrier Frequency Drift
EDR Relative Transmit power
EDR Carrier Frequency Stability and Modulation
Accuracy
EDR Differential Phase Encoding
EDR In-band Spurious Emissions
Enhanced Power Control
Sensitivity – Single Slot
Sensitivity – Multi Slot
C/I Performance
Blocking Performance
Inter-Modulation Performance
Maximum Input Level

Core-Test requirement for V3.0+HS,
V2.1+EDR,
V2.0+EDR and V1.2

Test

Test Method

***Bluetooth RF Conformance Test
(Antenna port measurement cont.)***

EDR Sensitivity
EDR BER Floor Performance
EDR C/I Performance
EDR Maximum Input Level

Temperature Exposure (-30 to 80)°C
Extreme Power Source Voltage (3 to 24)Vdc

Bluetooth RF.TS/3.0.H.1 section 6.5
Bluetooth RF.TS/3.0.H.1 section 6.5

Bluetooth Profiles

A2DP - Advanced Audio Distribution Profile
AVRCP - A/V Remote Control Profile
BIP - Basic Imaging Profile
BPP - Basic Printing Profile
DUN - Dial-up Networking Profile
FTP - File Transfer Profile
GAVDP - Generic A/V Distribution Profile
HFP - Hands-Free Profile
HSP - Headset Profile
OPP - Object Push Profile
PAN - Personal Area Network
PBAP - Phone Book Access Profile
SAP - Sim Access Profile
HID - Human Interface Device
CTP - Cordless Telephony Profile
ICP - Intercom Profile
IOPT - Interoperability Profile
DI - Device ID Profile
SYNC - Synchronization Profile
VDP - Video Distribution Profile
HDP - Health Device Profile
MAP - Message Access Profile
SDAP - Service Discovery Application Profile

CITA Bluetooth Compatibility Test Plan

¹Developed through the Bluetooth[®] Special Interest Group (SIG) with Bluetooth[®] Qualification Test Cases Reference List (TCRL) and Product Requirements available at <http://www.bluetooth.com/and> use of Bluetooth[®] SIG validated test system.